

STW56N65DM2

N-channel 650 V, 0.058 Ω typ., 48 A MDmesh™ DM2 Power MOSFET in a TO-247 package

Datasheet - production data

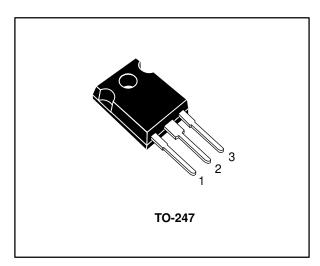
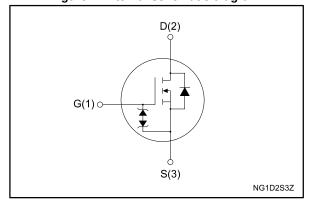


Figure 1: Internal schematic diagram



Features

Order code	V _{DS}	R _{DS(on)} max.	I _D	P _{TOT}
STW56N65DM2	650 V	0.065 Ω	48 A	360 W

- Fast-recovery body diode
- Extremely low gate charge and input capacitance
- Low on-resistance
- 100% avalanche tested
- Extremely high dv/dt ruggedness
- Zener-protected

Applications

Switching applications

Description

This high voltage N-channel Power MOSFET is part of the MDmesh TM DM2 fast recovery diode series. It offers very low recovery charge (Q_{rr}) and time (t_{rr}) combined with low $R_{DS(on)}$, rendering it suitable for the most demanding high efficiency converters and ideal for bridge topologies and ZVS phase-shift converters.

Table 1: Device summary

Order code	Marking	Package	Packing
STW56N65DM2	56N65DM2	TO-247	Tube

Contents STW56N65DM2

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STW56N65DM2 Electrical ratings

1 Electrical ratings

Table 2: Absolute maximum ratings

Symbol	Parameter	Value	Unit	
V _{GS}	Gate-source voltage	±25	V	
I.	Drain current (continuous) at T _{case} = 25 °C		۸	
l _D	Drain current (continuous) at T _{case} = 100 °C	30	Α	
I _{DM} ⁽¹⁾	Drain current (pulsed)	192	Α	
Ртот	Total dissipation at T _{case} = 25 °C	360	W	
dv/dt ⁽²⁾	Peak diode recovery voltage slope	50	V/ns	
dv/dt ⁽³⁾	MOSFET dv/dt ruggedness 5		V/IIS	
T _{stg}	Storage temperature		°C	
Tj	Operating junction temperature		C	

Notes:

Table 3: Thermal data

Symbol	Parameter	Value	Unit
R _{thj-case}	Thermal resistance junction-case	0.35	0000
R _{thj-amb}	Thermal resistance junction-ambient	50	°C/W

Table 4: Avalanche characteristics

Symbol	Parameter	Value	Unit
lar	Avalanche current, repetitive or not repetitive	7	Α
E _{AS} ⁽¹⁾	Single pulse avalanche energy	1300	mJ

Notes:

 $^{^{\}left(1\right)}$ Pulse width is limited by safe operating area.

 $^{^{(2)}}$ $I_{SD} \leq 48$ A, di/dt= 900 A/ μ s; V $_{DS}$ peak < V $_{(BR)DSS},~V_{DD}$ = 400 V

 $^{^{(3)}}$ V_{DS} \leq 520 V.

 $^{^{(1)}}$ starting T_{j} = 25 °C, I_{D} = $I_{AR},\ V_{DD}$ = 50 V.

2 Electrical characteristics

(T_{case} = 25 °C unless otherwise specified)

Table 5: Static

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
V _{(BR)DSS}	Drain-source breakdown voltage	$V_{GS} = 0 \text{ V}, I_D = 1 \text{ mA}$	650			V
	Zoro goto voltago drain	$V_{GS} = 0 \text{ V}, V_{DS} = 650 \text{ V}$			10	
I _{DSS}	Zero gate voltage drain current	V _{GS} = 0 V, V _{DS} = 650 V, T _{case} = 125 °C			100	μΑ
lgss	Gate-body leakage current	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 25 \text{ V}$			±5	μΑ
V _{GS(th)}	Gate threshold voltage	$V_{DS} = V_{GS}$, $I_D = 250 \mu A$	3	4	5	V
R _{DS(on)}	Static drain-source on- resistance	V _G S = 10 V, I _D = 24 A		0.058	0.065	Ω

Table 6: Dynamic

Symbol	Parameter Test conditions		Min.	Тур.	Max.	Unit
C _{iss}	Input capacitance		ı	4100	1	
Coss	Output capacitance	$V_{DS} = 100 \text{ V}, f = 1 \text{ MHz},$	ı	160	1	рF
Crss	Reverse transfer capacitance	$V_{GS} = 0 V$	ı	2.5	ı	μ.
Coss eq. (1)	Equivalent output capacitance	$V_{DS} = 0$ to 520 V, $V_{GS} = 0$ V	ı	375	ı	pF
R_{G}	Intrinsic gate resistance	$f = 1 \text{ MHz}, I_D = 0 \text{ A}$	1	4.1	-	Ω
Qg	Total gate charge	$V_{DD} = 520 \text{ V}, I_D = 48 \text{ A},$	-	88	1	
Qgs	Gate-source charge	V _{GS} = 10 V (see Figure 15: "Test circuit for gate charge	-	22	-	nC
Q_{gd}	Gate-drain charge	behavior")	ı	37	1	

Notes:

Table 7: Switching times

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
t _{d(on)}	Turn-on delay time	$V_{DD} = 325 \text{ V}, I_D = 24 \text{ A}$	-	28	-	
tr	Rise time	$R_G = 4.7 \Omega$, $V_{GS} = 10 V$ (see Figure 14: "Test circuit for	-	31	-	
t _{d(off)}	Turn-off delay time	resistive load switching	-	157	-	ns
tf	Fall time	times" and Figure 19: "Switching time waveform")	-	7.7	-	

 $^{^{(1)}}$ C_{oss eq.} is defined as a constant equivalent capacitance giving the same charging time as C_{oss} when V_{DS} increases from 0 to 80% V_{DSS}.

Table 8: Source-drain diode

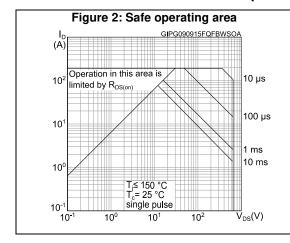
Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
I _{SD}	Source-drain current		1		48	Α
I _{SDM} ⁽¹⁾	Source-drain current (pulsed)		ı		192	Α
V _{SD} ⁽²⁾	Forward on voltage	$V_{GS} = 0 \text{ V}, I_{SD} = 48 \text{ A}$	1		1.6	V
t _{rr}	Reverse recovery time	$I_{SD} = 48 \text{ A}, \text{ di/dt} = 100 \text{ A/}\mu\text{s},$	-	135		ns
Qrr	Reverse recovery charge	V _{DD} = 100 V (see <i>Figure 16</i> : "Test circuit for inductive	1	0.68		μC
I _{RRM}	Reverse recovery current	load switching and diode recovery times")	-	10		Α
t _{rr}	Reverse recovery time	$I_{SD} = 48 \text{ A}, \text{ di/dt} = 100 \text{ A/}\mu\text{s},$	-	260		ns
Qrr	Reverse recovery charge	$V_{DD} = 100 \text{ V}, T_j = 150 \text{ °C}$ (see Figure 16: "Test circuit	-	2.75		μC
IRRM	Reverse recovery current	for inductive load switching and diode recovery times")	-	21		Α

Notes:

 $^{^{\}left(1\right) }$ Pulse width is limited by safe operating area.

 $^{^{(2)}}$ Pulse test: pulse duration = 300 $\mu s,$ duty cycle 1.5%.

2.1 Electrical characteristics (curves)



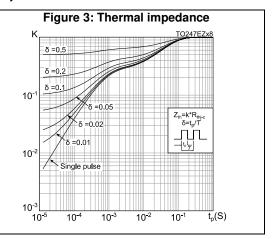


Figure 4: Output characteristics

(A)

140

120

100

80

60

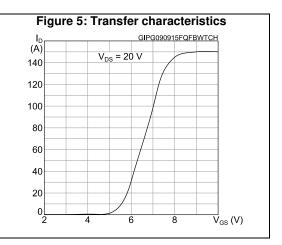
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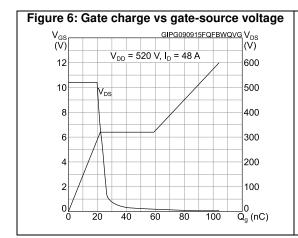
100

V_{GS} = 6 V

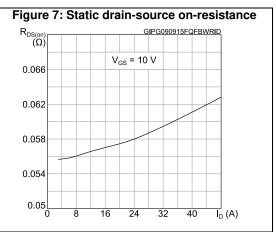
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0 4 8 12 16 V_{DS} (V)





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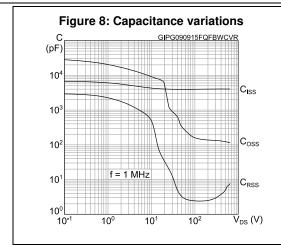


Figure 10: Normalized on-resistance vs temperature

R_{DS(on)} GIPG090915FQFBWRON

(norm.)

2.2

1.8

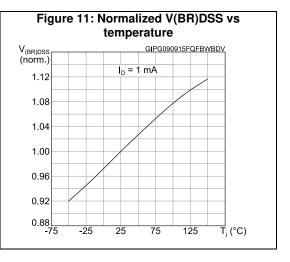
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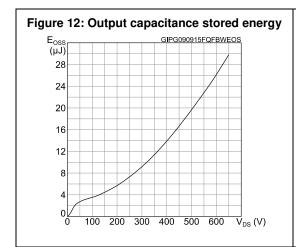
1.0

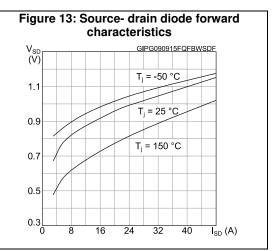
0.6

0.2

-75
-25
25
75
125
T_j (°C)





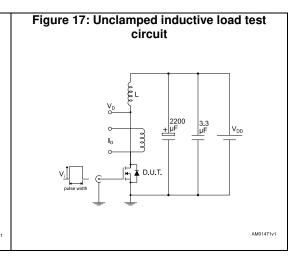


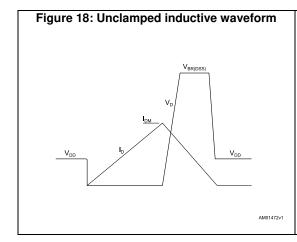
Test circuits STW56N65DM2

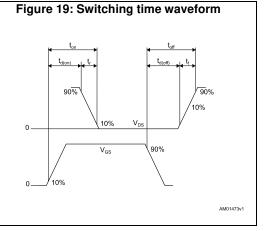
3 Test circuits

Figure 14: Test circuit for resistive load switching times

Figure 16: Test circuit for inductive load switching and diode recovery times







4 Package information

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK® packages, depending on their level of environmental compliance. ECOPACK® specifications, grade definitions and product status are available at: **www.st.com**. ECOPACK® is an ST trademark.

4.1 TO-247 package information

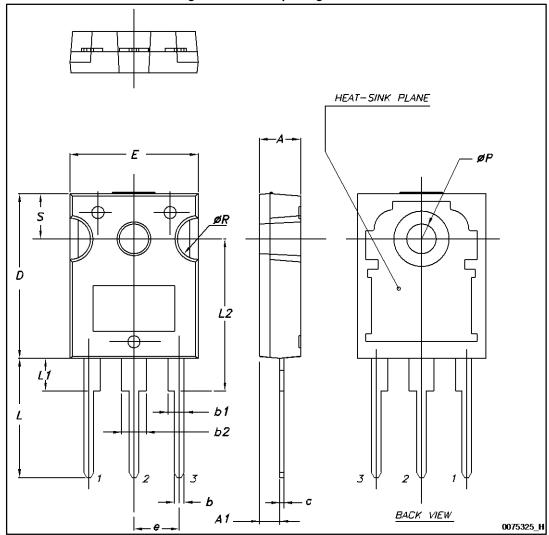


Figure 20: TO-247 package outline

Table 9: TO-247 package mechanical data

Dim		mm.	
Dim.	Min.	Тур.	Max.
А	4.85		5.15
A1	2.20		2.60
b	1.0		1.40
b1	2.0		2.40
b2	3.0		3.40
С	0.40		0.80
D	19.85		20.15
Е	15.45		15.75
е	5.30	5.45	5.60
L	14.20		14.80
L1	3.70		4.30
L2		18.50	
ØP	3.55		3.65
ØR	4.50		5.50
S	5.30	5.50	5.70

STW56N65DM2 Revision history

5 Revision history

Table 10: Document revision history

Date	Revision	Changes
27-Nov-2014	1	First release.
15-Sep-2015	2	Text and formatting changes throughout document. In section Electrical ratings: - updated tables Absolute maximum ratings and Avalanche characteristics In section Electrical characteristics: - updated and renamed table Static (was On/off states) - updated tables Dynamic, Switching times and Source-drain diode Updated section Electrical characteristics (curves)

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